DUSEU

MOSFET – N-Channel, QFET[®]

900 V, 8.0 A, 1.4 Ω

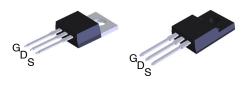
FQP9N90C, FQPF9N90CT

Description

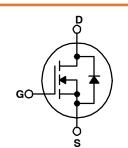
This N-Channel enhancement mode power MOSFET is produced using onsemi's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- 8 A 900 V, $R_{DS(on)} = 1.4 \Omega$ (Max.) @ $V_{GS} = 10$ V, $I_D = 4$ A
- Low Gate Charge (Typ. 45 nC)
- Low Crss (Typ. 14 pF)
- 100% Avalanche Tested
- This Device is Pb-Free Halide, Free and RoHS Compliant.



TO-220 TO-220 Fullpack, 3-Lead CASE 221A / TO-220F-3SG CASE 221AT



MARKING DIAGRAM



FQP9N90C,
FQPF9N90CT

А

ΖZ

- = Specific Device Code
- YWW

= Assembly Location

= Date Code (Year and Week)

= Assembly Lot Code

ORDERING INFORMATION

Device	Package	Shipping [†]
FQP9N90C	TO-220 (Pb-Free)	1000 Units / Tube
FQPF9N90CT	TO-220-3F (Pb-Free)	1000 Units / Tube

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

		Ra	Ratings		
Symbol	Parameter	FQP9N90C	FQPF9N90CT	Units	
V _{DSS}	Drain-Source Voltage	ç	900		
I _D	Drain Current – Continuous (T _C = 25°C) – Continuous (T _C = 100°C)	8.0 2.8	8.0* 2.8*	A	
I _{DM}	Drain Current – Pulsed (Note 1)	32	32*	А	
V _{GSS}	Gate-Source Voltage	<u>+</u>	±30		
E _{AS}	Single Pulsed Avalanche Energy (Note 2)	ç	900		
I _{AR}	Avalanche Current (Note 1)	٤	8.0		
E _{AR}	Repetitive Avalanche Energy (Note 1)	2	20.5		
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4	4.0		
P _D	Power Dissipation ($T_C = 25^{\circ}C$)	205	68	W	
	– Derate above 25°C	1.64	0.54	W/°C	
T _J ,T _{STG}	Operating and Storage Temperature Range	–55 t	–55 to +175		
ΤL	Maximum lead temperature for soldering, 1/8" from case for 5 seconds	3	300		

MOSFET MAXIMUM RATINGS (T_C = 25° C unless otherwise noted.)

*Drain current limited by maximum junction temperature. Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	FDP4D5N10C	FDPF4D5N10C	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.61	1.85	°C/W
$R_{\theta JS}$	Thermal Resistance, Case-to-sink Typ, Max.		-	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max	62.5	62.5	

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit		
Off Chara	Off Characteristics							
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I _D = 250 μ A	900	-	-	V		
$\frac{\Delta \text{BV}_{\text{DSS}}}{\Delta \text{T}_{\text{J}}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25° C	-	0.99	-	V/°C		
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 900 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	10	μΑ		
		V_{DS} = 720 V, T_{C} = 125°C	-	-	10	μA		
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$	-	-	100	nA		
I _{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -30 V, V_{DS} = 0 V	-	-	-100	nA		
On Charae	cteristics							
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	3.0	-	5.0	V		
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 4 \text{ A}$	-	1.12	1.4	Ω		
9 FS	Forward Transconductance	$V_{DS} = 40 \text{ V}, \text{ I}_{D} = 4 \text{ A}$	-	9.2	-	S		
Dynamic (Characteristics							
C _{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1.0 MHz	-	2100	2730	pF		
C _{oss}	Output Capacitance		-	175	230	pF		
C _{rss}	Reverse Transfer Capacitance]	_	14	18	pF		

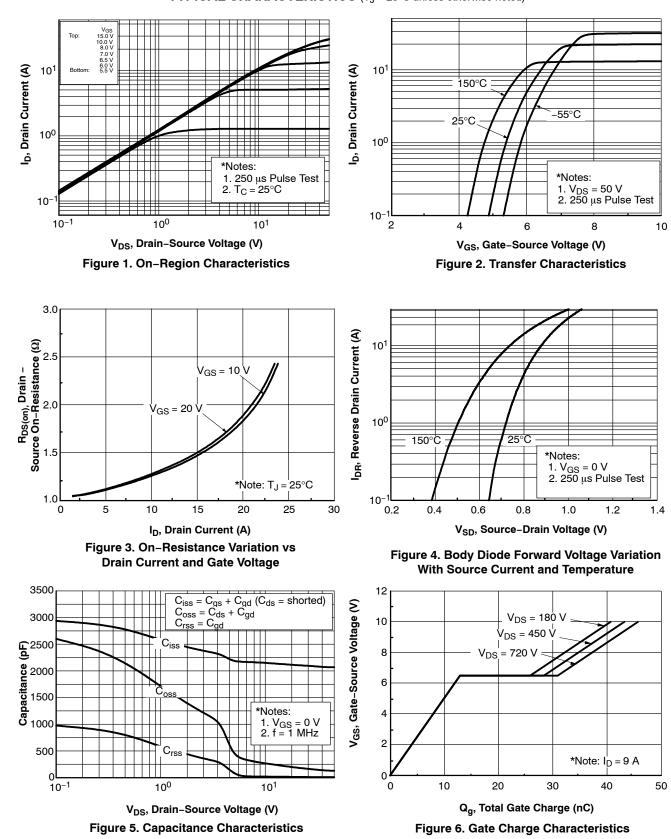
ELECTRICAL CHARACTERISTICS (continued) (T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 450 \text{ V}, \text{ I}_{D} = 9.0 \text{ A},$	-	50	110	ns
t _r	Turn–On Rise Time	R _G = 25 Ω (Note 4)	-	120	250	ns
t _{d(off)}	Turn-Off Delay Time		-	100	210	ns
t _f	Turn-Off Fall Time		-	75	160	ns
Qg	Total Gate Charge	V _{DS} = 720 V, I _D = 9.0 A, V _{GS} = 10 V (Note 4)	-	45	58	nC
Q _{gs}	Gate-Source Charge		-	13	-	nC
Q _{gd}	Gate-Drain Charge		-	18	_	nC
Drain-Sou	rce Diode Characteristics	-				
I _S	Maximum Continuous Drain-Source Diode Forward Current		-	-	8.0	А
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		-	-	32.0	А
V_{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 100 A	-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, V _{DD} = 50 V, I _F = 100 A, dI _F /dt = 100 A/µs	-	550	-	ns
Q _{rr}	Reverse Recovery Charge		-	6.5	-	μC

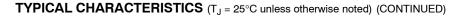
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

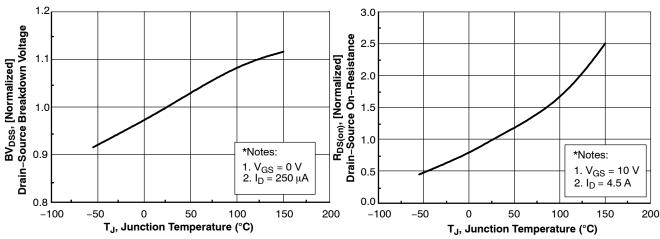
NOTES:

1. Repetitive Rating: Pulse width–limited by maximum junction temperature. 2. L = 21 mH, I_{AS} = 9 A, V_{DD} = 50 V, R_G = 25 Ω , starting T_J = 25°C. 3. I_{SD} ≤ 9.0 A, di/dt ≤ 200 A/µs, V_{DD} ≤ BV_{DSS}, starting T_J = 25°C. 4. Essentially independent of operating temperature.

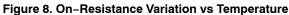


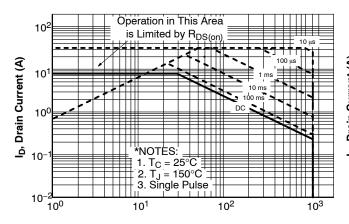
TYPICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted)



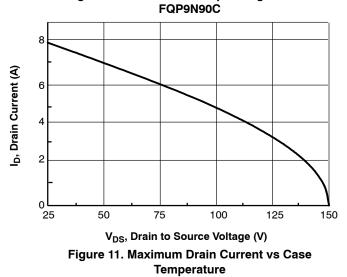


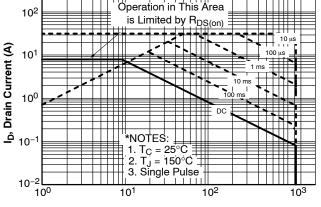






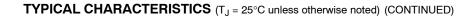


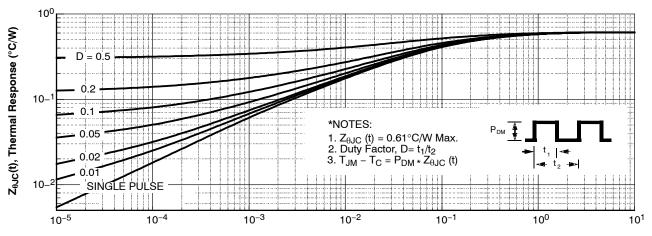




V_{DS}, Drain-Source Voltage (V)

Figure 10. Maximum Safe Operating Area for FQPF9N90CT







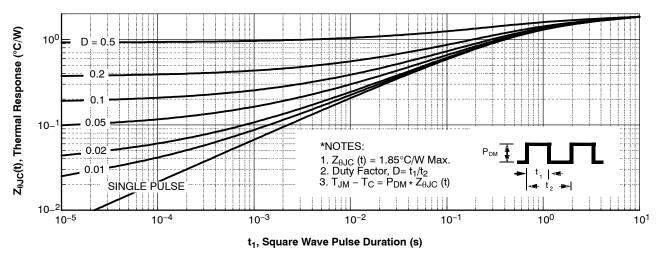


Figure 13. Transient Thermal Response Curve For FQPF9N90CT

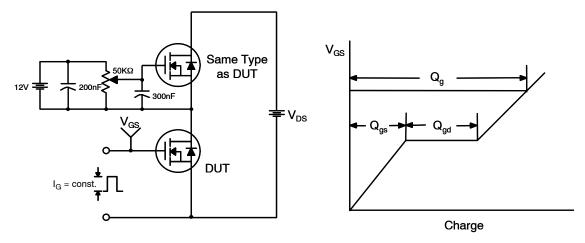


Figure 14. Gate Charge Test Circuit & Waveform

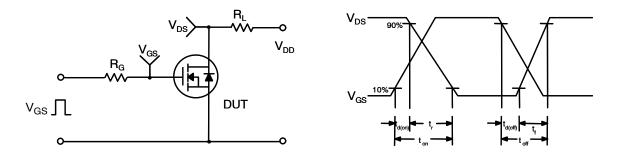


Figure 15. Resistive Switching Test Circuit & Waveforms

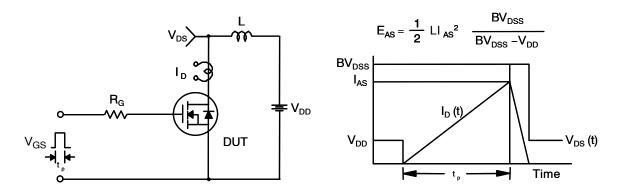


Figure 16. Unclamped Inductive Switching Test Circuit & Waveforms

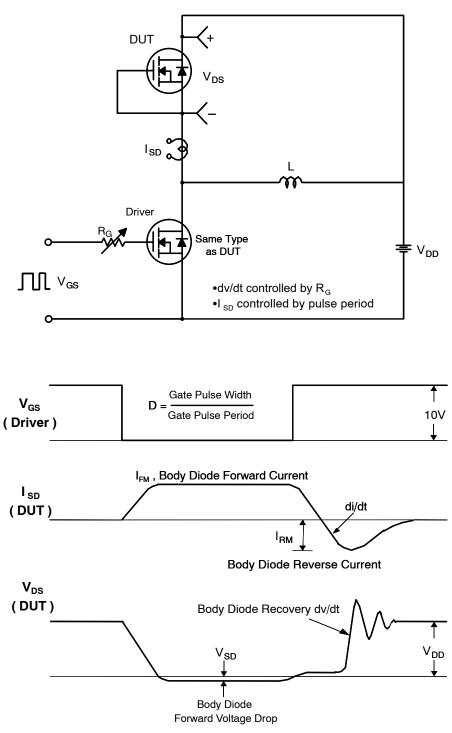
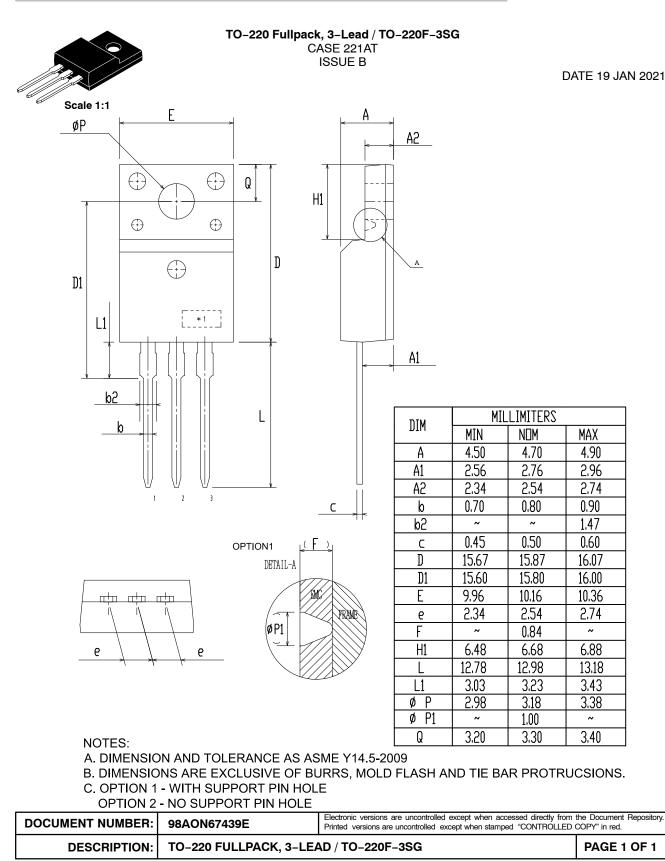


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms

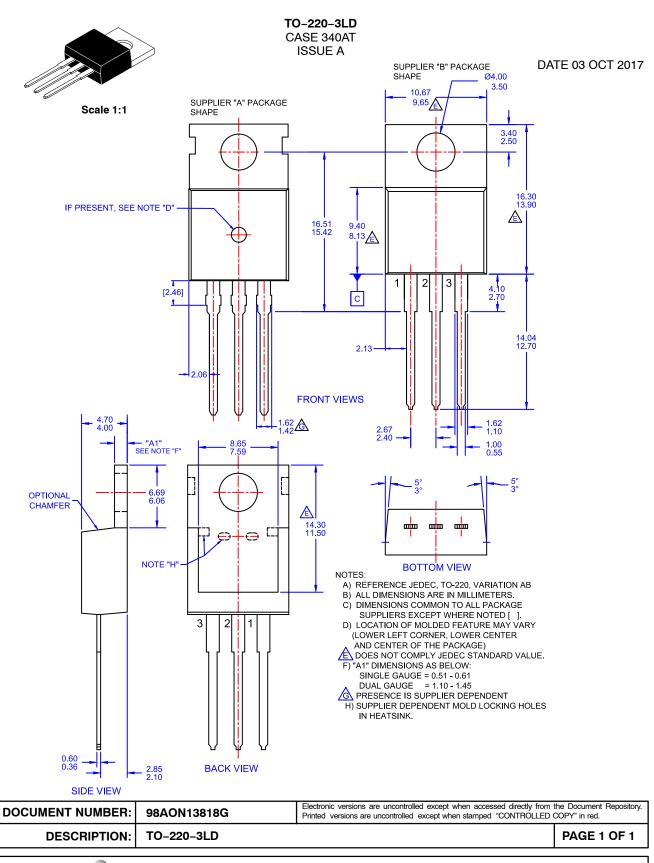
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